

**Notice of References Cited**Application/Control No.  
09/452,749Applicant(s)/Patent Under  
Reexamination  
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2814

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**NON-PATENT DOCUMENTS**

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	U	Shnirman et al. Quantum measuremetns performed with a single-electron transistor, 1998, Phys. Rev. B V57, pp15400-15407
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.